

**2018 Denver X-ray Conference ♦ Program-at-a-Glance ♦ Monday – Friday ♦ 6 – 10 August**

<b>Monday Morning Workshops 9:00 am – 12:00 Noon</b>				
<b>Meeting Rooms</b>				
	<b>Standley I</b>	<b>Standley II</b>	<b>Cotton Creek</b>	<b>Meadowbrook (Lake House when noted)</b>
XRD	Material Identification – The good, bad & ugly ( <b>Fawcett</b> )			Selecting Software for Rietveld Refinement I ( <b>Yakovenko</b> ) Lake House
XRF		Basic XRF ( <b>Anzelmo</b> )	Quantitative Analysis of XRF I ( <b>Elam</b> )	
<b>Monday Afternoon Workshops 1:30 pm – 4:30 pm</b>				
XRD	Quantitative Phase Analysis ( <b>Ryba</b> )	Two-Dimensional Detectors ( <b>He/Blanton</b> )		Selecting Software for Rietveld Refinement II ( <b>Yakovenko</b> ) Lake House
XRF			Quantitative Analysis of XRF II ( <b>Elam</b> )	Energy Dispersive XRF ( <b>Lemberge</b> )
<b>Monday Evening XRD Poster Session &amp; Reception 5:00 pm – 7:00 pm. (Watkins) Westminster Foyer</b>				
<b>Tuesday Morning Workshops 9:00 am – 12:00 Noon</b>				
Special Topic	Characterization of Thin Films ( <b>Hradil</b> )			
XRD		Line Profile Analysis ( <b>Leoni</b> )		
XRF			Micro XRF ( <b>Zaitz</b> )	Sample Preparation of XRF ( <b>Anzelmo</b> )
<b>Tuesday Afternoon Workshops 1:30 pm – 4:30 pm</b>				
Special Topic	Imaging ( <b>Vogt</b> )			
XRD		Non-Ambient ( <b>Misture</b> )		
XRF			Trace Analysis ( <b>Strel/Wobrauschek</b> )	Handheld XRF – The Silver Bullet or Fools Gold? ( <b>Loubser</b> )
<b>Tuesday Evening XRF Poster Session &amp; Reception 5:00 pm – 7:00 pm. (Schmeling) Westminster Foyer</b>				
<b>Wednesday Morning Plenary Session, Minerals and Gems Standley I &amp; II, 8:30 am – 11:45 am (Blanton)</b>				
<b>Wednesday Afternoon Sessions</b>				
Special Topic	New Developments in XRD & XRF Instrumentation I ( <b>Fawcett</b> )	Microcalorimeter Detectors & Applications ( <b>Ullom</b> )		
XRD			Non-Ambient ( <b>Misture</b> )	
XRF				Industrial Applications of XRF ( <b>Broton</b> )
<b>Wednesday Evening Vendor Sponsored Reception 5:30 pm - 7:00 pm. Exhibit Hall</b>				
<b>Thursday Morning Sessions</b>				
Special Topic	New Developments in XRD & XRF Instrumentation II ( <b>Fawcett</b> )			
XRD		Rietveld ( <b>Kaduk</b> )		
XRF			Trace Analysis including TXRF ( <b>Borgese</b> )	
<b>Thursday Afternoon Sessions</b>				
Special Topic	Cultural Heritage ( <b>Van Grieken/Schmeling</b> )			
XRD		General XRD ( <b>Murray</b> )		
XRF			Advanced Fundamental Parameters ( <b>Ullom</b> )	General XRF ( <b>Fittschen/Vaidya</b> )
<b>Friday Morning Sessions</b>				
Special Topic				Imaging ( <b>Tsuji/Meirer</b> )
XRD	Advanced Methods ( <b>Watkins/Rodriguez</b> )	Industrial Applications of XRD ( <b>Noyan</b> )		
XRF			Quantitative Analysis of XRF ( <b>Brehm</b> )	